Course guides
230645 - MNT - Micro and Nanotechnologies

Unit in charge: Barcelona School of Telecommunications Engineering
Teaching unit: 710 - EEL - Department of Electronic Engineering.

Degree:
MASTER'S DEGREE IN ELECTRONIC ENGINEERING (Syllabus 2013). (Compulsory subject).
MASTER'S DEGREE IN TELECOMMUNICATIONS ENGINEERING (Syllabus 2013). (Optional subject).
MASTER'S DEGREE IN ADVANCED TELECOMMUNICATION TECHNOLOGIES (Syllabus 2019). (Optional subject).

Academic year: 2019  ECTS Credits: 5.0  Languages: English

LECTURER

Coordinating lecturer: JOSEP CALDERER CARDONA
Others: ÁNGEL RODRÍGUEZ MARTÍNEZ

DEGREE COMPETENCES TO WHICH THE SUBJECT CONTRIBUTES

Specific:
1. Ability to use semiconductor devices taking into account their physical characteristics and limitations.
2. Ability to analyze and evaluate the performance at the physical level of the main devices and sensors, the relations between magnitudes in their terminals and their equivalent circuits.
3. Ability to establish a relationship between an electronic device and its fabrication technology, and to understand its design process.

Transversal:
4. TEAMWORK: Being able to work in an interdisciplinary team, whether as a member or as a leader, with the aim of contributing to projects pragmatically and responsibly and making commitments in view of the resources that are available.
5. EFFECTIVE USE OF INFORMATION RESOURCES: Managing the acquisition, structuring, analysis and display of data and information in the chosen area of specialisation and critically assessing the results obtained.
6. FOREIGN LANGUAGE: Achieving a level of spoken and written proficiency in a foreign language, preferably English, that meets the needs of the profession and the labour market.

TEACHING METHODOLOGY

- Lectures
- Application classes
- Group work (distance)
- Individual work (distance)
- Exercises
- Oral presentations
- Other activities: visit to laboratories
- Short answer test (Control)
- Short answer test (Test)
- Extended answer test (Final Exam)
LEARNING OBJECTIVES OF THE SUBJECT

Learning objectives of the subject:

The aim of this course is the understanding of physical and technological basis of electronic devices in order to use innovative solutions to electronic design problems. Emphasis is on MOS field-effect transistors and their behaviors (Fin FET, TFT, etc), Power devices, Nano devices and sensors.

Learning results of the subject:

- Ability to use modelling tools of semiconductor devices.
- Ability to define basic fabrication processes.
- Ability to decide between technological alternatives.

STUDY LOAD

<table>
<thead>
<tr>
<th>Type</th>
<th>Hours</th>
<th>Percentage</th>
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<tbody>
<tr>
<td>Self study</td>
<td>86.0</td>
<td>68.80</td>
</tr>
<tr>
<td>Hours large group</td>
<td>39.0</td>
<td>31.20</td>
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Total learning time: 125 h

CONTENTS

1. Field effect transistors and advanced devices

Description:
- Review of Metal-oxide-semiconductor field effect transistor (MOSFET) standard model
- MOSFET downscaling
- Thin film transistors (TFT)
- Junction (JFET) and Metal-semiconductor (MESFET) field effect transistors
- Devices based on heterojunctions: High Electron Mobility Transistors (HEMT) and Heterojunction Bipolar Transistors (HBT)
- Advanced topics

2. Power devices

Description:
- Diodes
- Bipolar transistors
- Thyristors (SCR, DIAC, TRIAC, etc.)
- Metal-oxide-semiconductor field effect transistor (MOSFET)
- Insulated gate bipolar transistor (IGBT)

3. Fabrication technology

Description:
- Semiconductor materials
- Doping techniques
- Layer growth
- Lithography
- Epitaxy
- Process integration
4. Sensors

Description:
- Mechanical
- Chemical
- Electromagnetic
- Optical
- Thermal

5. Advanced Materials

Description:
- Carbon nanotubes
- Polymers
- Porous silicon

ACTIVITIES

EXERCISES

Description:
Exercises to strengthen the theoretical knowledge.

MIDTERM EXAMINATION

Description:
Test on the evolution of students by half semester.

EXTENDED ANSWER TEST (FINAL EXAMINATION)

Description:
Final examination.

GRADING SYSTEM

Final examination: from 60%
Individual assessments: from 40%

BIBLIOGRAPHY

Basic:

Complementary:
- Mitin, V.V.; Kochelap, V.A.; Strocio, M.A. Introduction to nanoelectronics: science, nanotechnology, engineering, and applications.